

**MIRROR BLANK MATERIAL, AdLIGO BS MIRROR**

APPROVALS	DATE	REV	DCN NO.	BY	CHECK	DCC	DATE
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CHECKED: G Billingsley	04/04/08	A					
APPROVED:							
DCC RELEASE							

Applicable Documents

LIGO-D080050-A AdLIGO BS Mirror Blank

MIL-G-174-B Glass, Optical

Requirements

Physical Dimensions per LIGO- D080050-A AdLIGO BS Mirror Blank

Clear Aperture Central 315 mm

Serial Number Blanks shall be serialized as BSXX, where XX increments starting at 01

Material Low Inclusion Fused Silica

Final shaping Shaping shall be performed using a progression of grit size ending with a 320 or smaller grit tool.

Defect depth Maximum on any surface or corner is less than 0.5 mm

Index Homogeneity in central 110 mm $\leq 5.0 \times 10^{-7}$ P-VIndex Homogeneity in clear aperture $\leq 2.5 \times 10^{-6}$ P-VBirefringence ≤ 1 nm/cm within the clear aperture
 ≤ 5 nm/cm outside the clear apertureBubble and Inclusion Cross section Total ≤ 0.01 mm²/100cm³
Within the clear aperture Inclusions with a diameter of 10 μ m or less are not included in the total.
Note all inclusionsMaximum inclusion diameter ≤ 0.1 mm

Striae Class 1

OH Content ≤ 1 ppm

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Specification	Method	Frequency of Inspection	Data Delivered
Physical Dimensions	Visual Inspection	100%	Diameter Thickness
Serial number	Visual Inspection	100%	Inspection Report included with Certification
Material	Process Control Material Certification	100%	Inspection Report included with Certification
Defect depth	Visual Inspection	100%	Hand sketch indicating location and dimensions
Homogeneity	Interferometric Measurement	100%	Inspection Report included with Certification
Birefringence	MIL-G-174 Section 4.4.5	100%	Inspection Report included with Certification
Inclusions	Visual Inspection	100%	Hand sketch indicating location and dimensions
Striae	MIL-G-174 Section 4.4.6, method 1 or 2 (in optical axis only)	100%	Inspection Report included with Certification
OH content	Measurement	100%	Inspection Report included with Certification

Table 1: MEASUREMENT MATRIX: FREQUENCY AND METHOD